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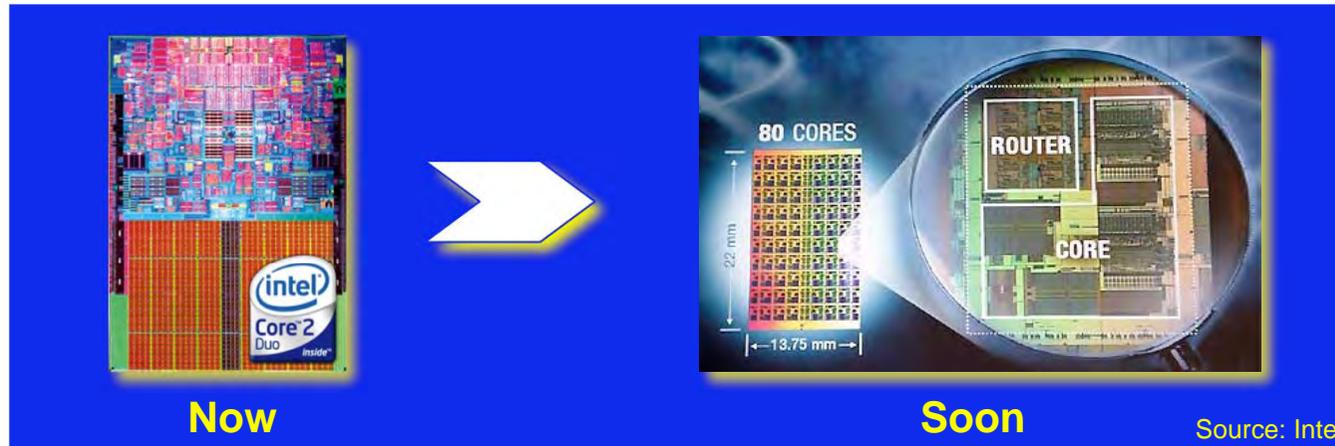
# Fault Tolerance of the Input/Output Ports in Massively Defective Multicore Processor Chips

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# From Multi-Cores Architectures To Multi-Multi-Cores Architectures

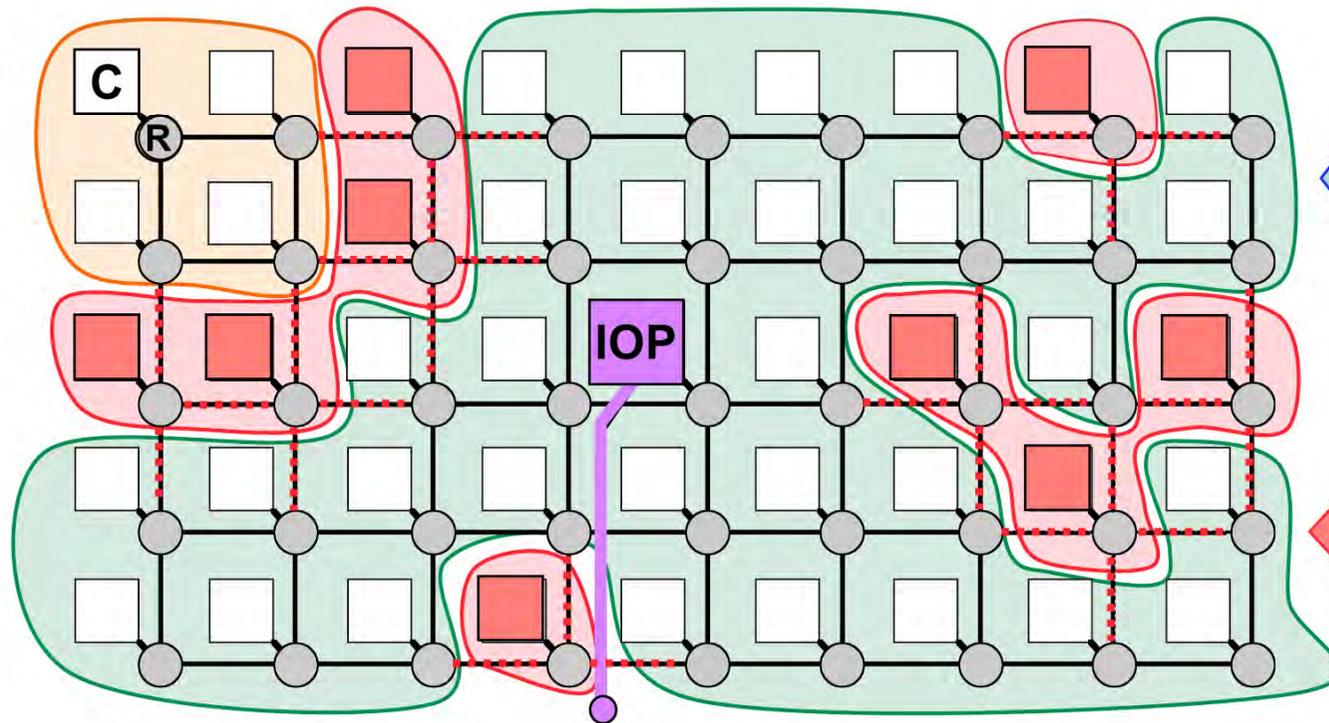


- Multi-Core: ↗ performance while coping with power dissipation issues (very high clock frequency)
- Still, ↘ transistor size for including many of such cores  
—> significant % of defective cores (more than 10% ?)
- Current context:
  - ◆ Chips are sorted according to frequency
  - ◆ Single core processor = “Downgraded” dual core circuits ...
- How to go further: **On-line reconfiguration to cope with faults?**

# Example Target Architecture

(5x9-node Network — Connectivity: 4)

Disconnected  
Zone →



Single  
Connected  
Zone ←

Mutual  
Diagnosis  
v  
Bad Cores  
Isolated ←



- The I/O Interface (IOP) is a Hardcore and a “Blottle Neck”

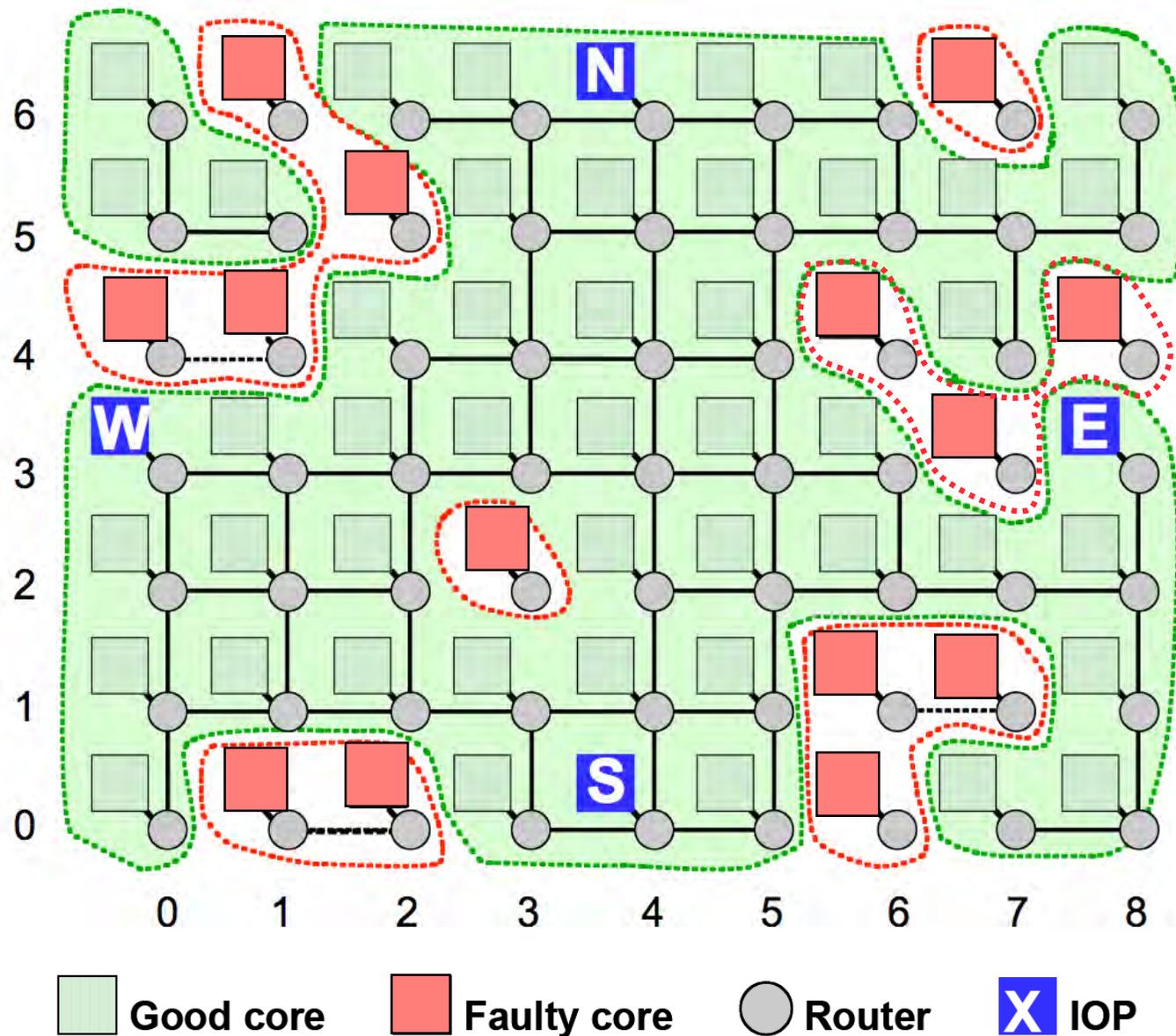
P. Zajač, J. H. Collet,  
J. Arlat, Y. Crouzet,  
“Resilience through  
Self-Configuration in  
Future Massively  
Defective Nanochips”,  
Supplemental Volume  
DSN2007, Edinburgh,  
Scotland, UK,  
pp.266-271, 2007

# Preliminary Analysis of Several Options

- Increase the number of I/O ports
- Consider redundant IOPs
- Extend IOP connectivity with grid (adjacent nodes)
- ...

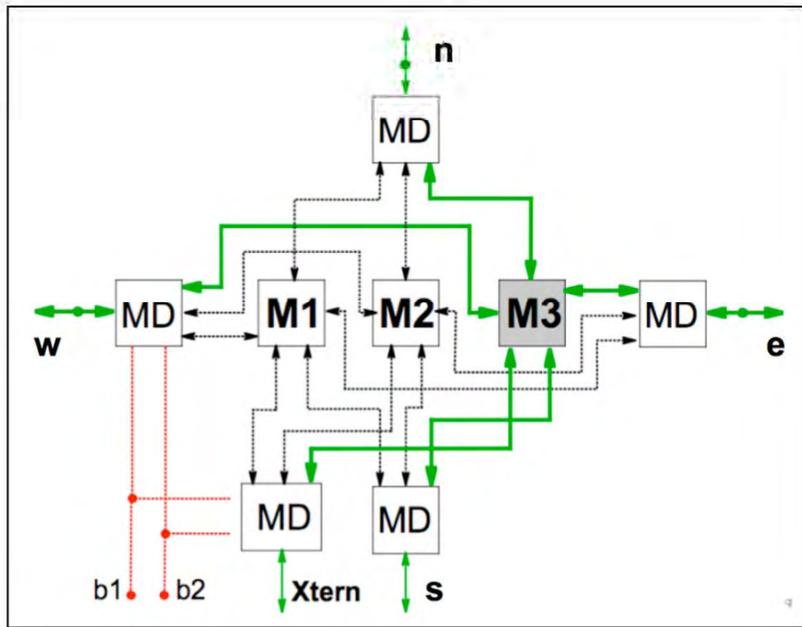
# Increasing the Number of IOPs

Example of a 4-IOP Grid Including 14 Defective Cores



# Redundant IOP Architecture

Example:  
4-connect RIOP  
with  $R = 3$  Redundant I/O Modules ( $M_i$ )

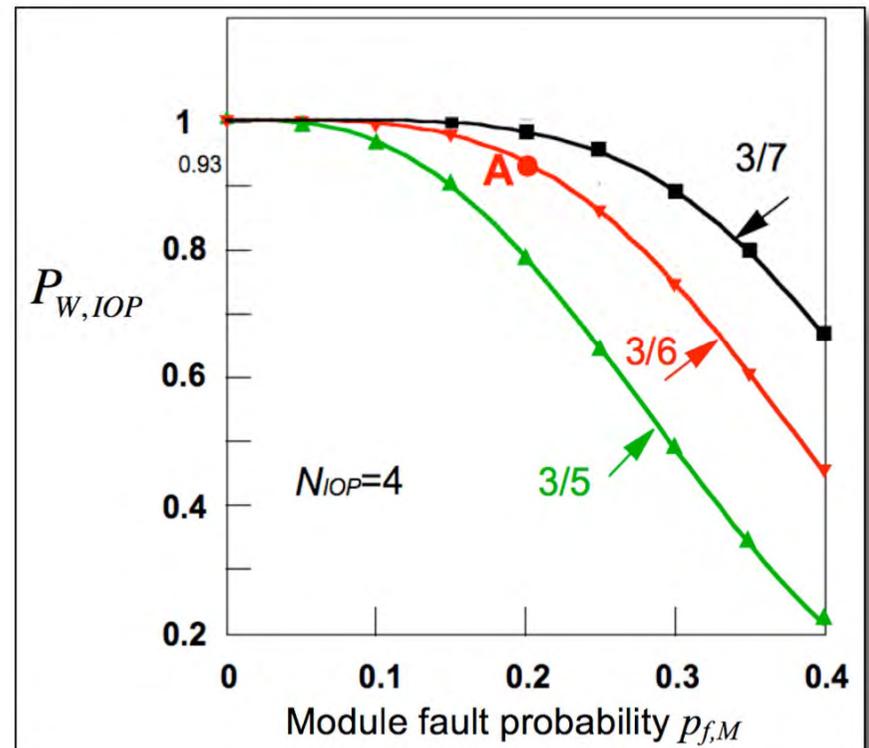


**Chip Validation Criteria?**  
At least  $r$  out of  $R$  modules  
are fault-free at start-up in each RIOP

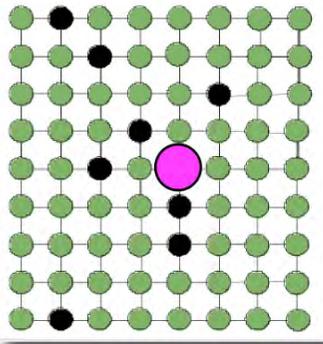
Validation probability

$$P_{W, IOP} = \left[ \sum_{i=3}^R \binom{R}{i} (1 - p_{f,M})^i p_{f,M}^{R-i} \right]^{N_{IO}}$$

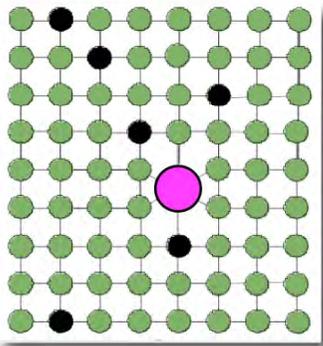
Example:  
Case of a 4-port Chip for  $R = 5, 6, 7$   
and  $r = 3$



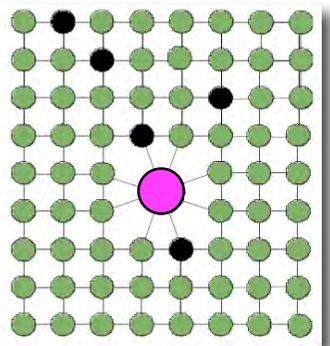
# Modification of Grid Topology around each RIOP



Connectivity  $n_c = 4$



Connectivity  $n_c = 6$



Connectivity  $n_c = 8$

RIOP

Prob.  $k/n_c$  nodes adj / RIOP are OK

$$P_L(k, n_c, p_{f,N}) = \left[ \sum_{i=k}^{n_c} \binom{n_c}{i} (1 - p_{f,N})^i p_{f,N}^{n_c-i} \right]^{N_{IO}}$$

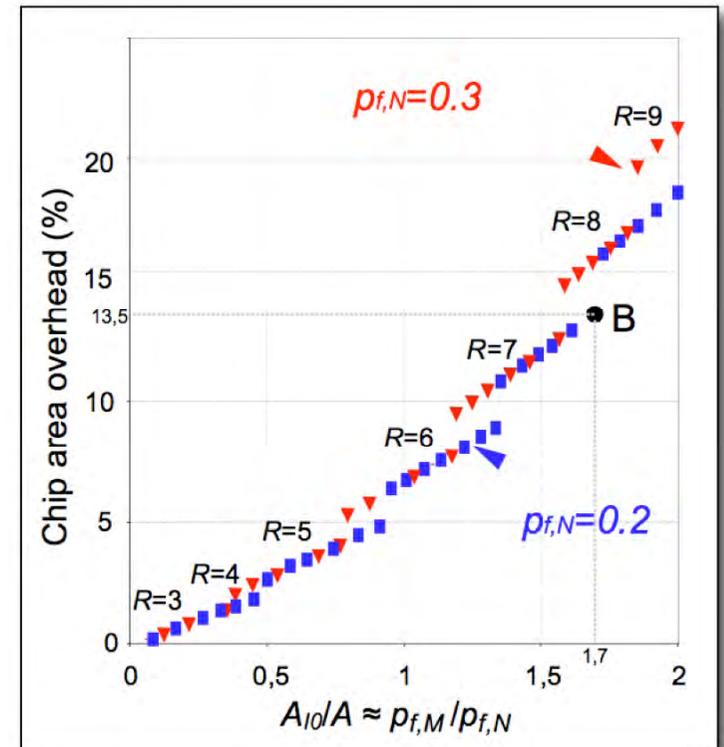
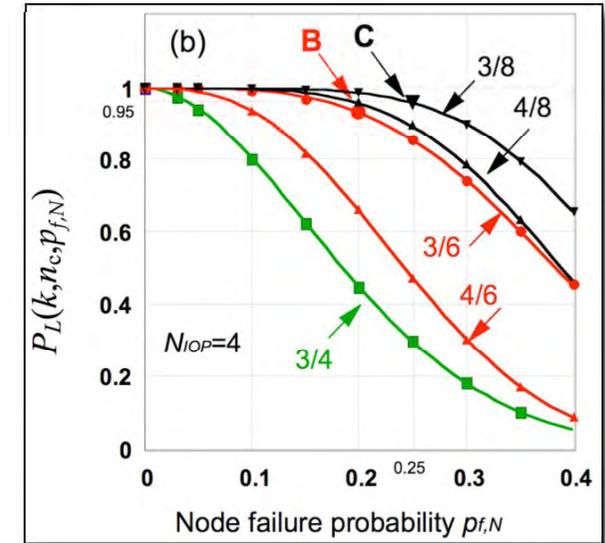
Example of Overhead Analysis

$N = 300$ ;  $N_{IO} = 4$ ;  $n_c = 8$

VC1: To protect communication bandwidth of each RIOP, at least 3/8 neighboring nodes must be fault-free.

VC2: Validation yield threshold:  $P_{W,IO} \times P_L(k, n_c, p_{f,N}) \geq 80\%$ .

$$Q = \frac{(R-1) N_{IO} \cdot A_{IO}}{N \cdot A}$$



# Concluding Remarks

- Study of the protection of the IOPs in multiport grid architectures
- Analysis of the dependability gain and overhead induced: redundancy, connectivity and chip area
- Grid topology and connectivity
- Self-diagnosis and coverage
- Application reconfiguration